Topics in Statistical Data Analysis for HEP

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Abstract
These lectures concern two topics that are becoming increasingly important in the analysis of High Energy Physics (HEP) data: Bayesian statistics and multivariate methods. In the Bayesian approach we extend the interpretation of probability to cover not only the frequency of repeatable outcomes but also to include a degree of belief. In this way we are able to associate probability with a hypothesis and thus to answer directly questions that cannot be addressed easily with traditional frequentist methods. In multivariate analysis we try to exploit as much information as possible from the characteristics that we measure for each event to distinguish between event types. In particular we will look at a method that has gained popularity in HEP in recent years: the boosted decision tree (BDT).

1 Introduction

When an HEP experiment enters the phase of data collection and analysis, the daily tasks of its postgraduate students are often centred not around the particle physics theories one is trying to test but rather on statistical methods. These methods are the tools needed to compare data with theory and quantify the extent to which one stands in agreement with the other. Of course one must understand the physical basis of the models being tested and so the theoretical emphasis in postgraduate education is no doubt well founded. But with the increasing cost of HEP experiments it has become important to exploit as much of the information as possible in the hard-won data, and to quantify as accurately as possible the inferences one draws when confronting the data with model predictions.

Despite efforts to make the lectures self contained, some familiarity with basic ideas of statistical data analysis is assumed. Introductions to the subject can be found, for example, in the reviews of the Particle Data Group [1] or in the texts [2, 3, 4, 5, 6].

In these two lectures we will discuss two topics that are becoming increasingly important: Bayesian statistics and multivariate methods. In Sec. 2 we will review briefly the concept of probability and see how this is used differently in the frequentist and Bayesian approaches. Then in Sec. 2.2 we will discuss a simple example, the fitting of a straight line to a set of measurements, in both the frequentist and Bayesian approaches and compare different aspects of the two. This will include in Sec. 2.2.3 a brief description of Markov Chain Monte Carlo (MCMC), one of the most important tools in Bayesian computation. We generalize the treatment in Sec. 2.3 to include systematic errors.

In Sec. 3 we take up the general problem of how to distinguish between two classes of events, say, signal and background, on the basis of a set of characteristics measured for each event. We first describe how to quantify the performance of a classification method in the framework of a statistical test. Although the Neyman–Pearson lemma indicates that this problem has an optimal solution using the likelihood ratio, this usually cannot be used in practice and one is forced to seek other methods. In Sec. 3.1 we look at a specific example of such a method, the boosted decision tree. Using this example we describe several issues common to many classification methods, such as overtraining. Finally, some conclusions are mentioned in Sec. 4.

2 Bayesian statistical methods for HEP

In this section we look at the basic ideas of Bayesian statistics and explore how these can be applied in particle physics. We will contrast these with the corresponding notions in frequentist statistics, and to

make the treatment largely self contained, the main ideas of the frequentist approach will be summarized as well.

2.1 The role of probability in data analysis

We begin by defining probability with the axioms written down by Kolmogorov [7] using the language of set theory. Consider a set S containing subsets $A, B, \ldots$. We define the probability P as a real-valued function with the following properties:

1. For every subset A in S, $P(A) \geq 0$;
2. For disjoint subsets (i.e., $A \cap B = \emptyset$), $P(A \cup B) = P(A) + P(B)$;
3. $P(S) = 1$.

In addition, we define the conditional probability $P(A|B)$ (read P of A given B) as

$$P(A|B) = \frac{P(A \cap B)}{P(B)} \, . \tag{1}$$

From this definition and using the fact that $A \cap B$ and $B \cap A$ are the same, we obtain *Bayes' theorem*,

$$P(A|B) = \frac{P(B|A)P(A)}{P(B)} \, . \tag{2}$$

From the three axioms of probability and the definition of conditional probability, we can derive the *law of total probability*,

$$P(B) = \sum_i P(B|A_i)P(A_i) \, , \tag{3}$$

for any subset B and for disjoint A_i with $\cup_i A_i = S$. This can be combined with Bayes' theorem (2) to give

$$P(A|B) = \frac{P(B|A)P(A)}{\sum_i P(B|A_i)P(A_i)} \, , \tag{4}$$

where the subset A could, for example, be one of the A_i.

The most commonly used interpretation of the subsets of the sample space are outcomes of a repeatable experiment. The probability $P(A)$ is assigned a value equal to the limiting frequency of occurrence of A. This interpretation forms the basis of *frequentist statistics*.

The subsets of the sample space can also be interpreted as *hypotheses*, i.e., statements that are either true or false, such as 'The mass of the W boson lies between 80.3 and 80.5 GeV.' In the frequency interpretation, such statements are either always or never true, i.e., the corresponding probabilities would be 0 or 1. Using *subjective probability*, however, $P(A)$ is interpreted as the degree of belief that the hypothesis A is true.

Subjective probability is used in *Bayesian* (as opposed to frequentist) statistics. Bayes' theorem can be written

$$P(\text{theory}|\text{data}) \propto P(\text{data}|\text{theory})P(\text{theory}) \, , \tag{5}$$

where 'theory' represents some hypothesis and 'data' is the outcome of the experiment. Here $P(\text{theory})$ is the *prior* probability for the theory, which reflects the experimenter's degree of belief before carrying

out the measurement, and $P(\text{data}|\text{theory})$ is the probability to have gotten the data actually obtained, given the theory, which is also called the *likelihood*.

Bayesian statistics provides no fundamental rule for obtaining the prior probability; this is necessarily subjective and may depend on previous measurements, theoretical prejudices, etc. Once this has been specified, however, Eq. (5) tells how the probability for the theory must be modified in the light of the new data to give the *posterior* probability, $P(\text{theory}|\text{data})$. As Eq. (5) is stated as a proportionality, the probability must be normalized by summing (or integrating) over all possible hypotheses.

The difficult and subjective nature of encoding personal knowledge into priors has led to what is called *objective Bayesian statistics*, where prior probabilities are based not on an actual degree of belief but rather derived from formal rules. These give, for example, priors which are invariant under a transformation of parameters or which result in a maximum gain in information for a given set of measurements. For an extensive review see, e.g., Ref. [8].

2.2 An example: fitting a straight line

In Section 2.2 we look at the example of a simple fit in both the frequentist and Bayesian frameworks. Suppose we have independent data values y_i, $i = 1, ..., n$, that are each made at a given value x_i of a control variable x. Suppose we model the y_i as following a Gaussian distribution with given standard deviations σ_i and mean values μ_i given by a function that we evaluate at the corresponding x_i,

$$\mu(x; \theta_0, \theta_1) = \theta_0 + \theta_1 x \ . \tag{6}$$

We would like to determine values of the parameters θ_0 and θ_1 such that the model best describes the data. The ingredients of the analysis are illustrated in Fig. 1(a).

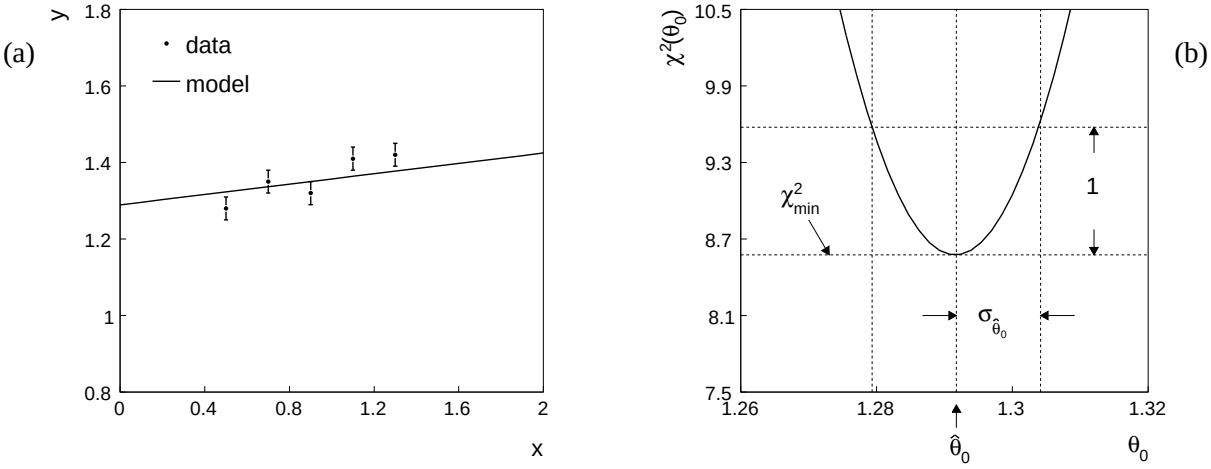

Fig. 1: (a) Illustration of fitting a straight line to data (see text). (b) The χ^2 as a function of the parameter θ_0, illustrating the method to determine the estimator $\hat{\theta}_0$ and its standard deviation $\sigma_{\hat{\theta}_0}$.

Now suppose the real goal of the analysis is only to estimate the parameter θ_0. The slope parameter θ_1 must also be included in the model to obtain a good description of the data, but we are not interested in its value as such. We refer to θ_0 as the parameter of interest, and θ_1 as a *nuisance parameter*. In the following sections we treat this problem using both the frequentist and Bayesian approaches.

2.2.1 The frequentist approach

Our model states that the measurements are Gaussian distributed, i.e., the probability density function (pdf) for the ith measurement y_i is

$$f(y_i;\boldsymbol{\theta}) = \frac{1}{\sqrt{2\pi}\sigma_i} e^{-(y_i-\mu(x_i;\boldsymbol{\theta}))^2/2\sigma_i^2} \ , \tag{7}$$

where $\boldsymbol{\theta} = (\theta_0, \theta_1)$.

The *likelihood function* is the joint pdf for all of the y_i, evaluated with the y_i obtained and regarded as a function of the parameters. Since we are assuming that the measurements are independent, the likelihood function is in this case given by the product

$$L(\boldsymbol{\theta}) = \prod_{i=1}^{n} f(y_i;\boldsymbol{\theta}) = \prod_{i=1}^{n} \frac{1}{\sqrt{2\pi}\sigma_i} e^{-(y_i-\mu(x_i;\boldsymbol{\theta}))^2/2\sigma_i^2} \ . \tag{8}$$

In the frequentist approach we construct estimators $\hat{\boldsymbol{\theta}}$ for the parameters $\boldsymbol{\theta}$, usually by finding the values that maximize the likelihood function. (We will write estimators for parameters with hats.) In this case one can see from (8) that this is equivalent to minimizing the quantity

$$\chi^2(\boldsymbol{\theta}) = \sum_{i=1}^{n} \frac{(y_i - \mu(x_i;\boldsymbol{\theta}))^2}{\sigma_i^2} = -2\ln L(\boldsymbol{\theta}) + C \ , \tag{9}$$

where C represents terms that do not depend on the parameters. Thus for the case of independent Gaussian measurements, the maximum likelihood (ML) estimators for the parameters coincide with those of the method of least squares (LS).

Suppose first that the slope parameter θ_1 is known exactly, and so it is not adjusted to maximize the likelihood (or minimize the χ^2) but rather held fixed. The quantity χ^2 versus the single adjustable parameter θ_0 would be as shown in Fig. 1(b), where the minimum indicates the value of the estimator $\hat{\theta}_0$.

Methods for obtaining the standard deviations of estimators — the statistical errors of our measured values — are described in many references such as [1, 2, 3, 4, 5, 6]. Here in the case of a single fitted parameter the rule boils down to moving the parameter away from the estimate until χ^2 increases by one unit (i.e., $\ln L$ decreases from its maximum by $1/2$) as indicated in the figure.

It may be, however, that we do not know the value of the slope parameter θ_1, and so even though we do not care about its value in the final result, we are required to treat it as an adjustable parameter in the fit. Minimizing $\chi^2(\boldsymbol{\theta})$ results in the estimators $\hat{\boldsymbol{\theta}} = (\hat{\theta}_0, \hat{\theta}_1)$, as indicated schematically in Fig. 2(a). Now the recipe to obtain the statistical errors, however, is not simply a matter of moving the parameter away from its estimated value until the χ^2 goes up by one unit. Here the standard deviations must be found from the tangent lines (or in higher-dimensional problems, the tangent hyperplanes) to the contour defined by $\chi^2(\boldsymbol{\theta}) = \chi^2_{\min} + 1$, as shown in the figure.

The tilt of the contour in Fig. 2(a) reflects of the correlation between the estimators $\hat{\theta}_0$ and $\hat{\theta}_1$. A useful estimate for the inverse of the matrix of covariances $V_{ij} = \mathrm{cov}[V_i, V_j]$ can be found from the second derivative of the log-likelihood evaluated at its maximum,

$$\widehat{V}_{ij}^{-1} = -\left.\frac{\partial^2 \ln L}{\partial\theta_i \partial\theta_j}\right|_{\boldsymbol{\theta}=\hat{\boldsymbol{\theta}}} \ . \tag{10}$$

More information on how to extract the full covariance matrix from the contour can be found, for example, in Refs. [1, 2, 3, 4, 5, 6]. The point to note here is that the correlation between the estimators for the parameter of interest the nuisance parameter has the result of inflating the standard deviations of both. That is, if θ_1 were known exactly, then the distance one would have to move θ_0 away from its estimated value to make the χ^2 increase by one unit would be less, as one can see from the figure. So although we can improve the ability of a model to describe the data by including additional nuisance parameters, this

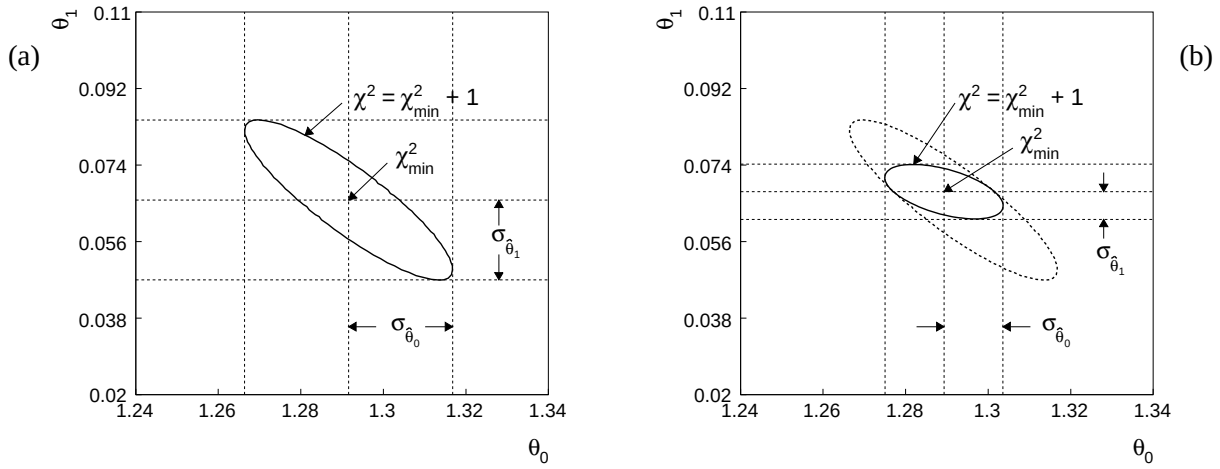

Fig. 2: Contour of $\chi^2(\boldsymbol{\theta}) = \chi^2_{\rm min} + 1$ centred about the estimates $(\hat{\theta}_0, \hat{\theta}_1)$ (a) with no prior measurement of θ_1 and (b) when a prior measurement of θ_1 is included.

comes at the price of increasing the statistical errors. This is an important theme which we will encounter often in data analysis.

Now consider the case where we have a prior measurement of θ_1. For example, we could have a measurement t_1 which we model as following a Gaussian distribution centred about θ_1 and having a given standard deviation σ_{t_1}. If this measurement is independent of the other y_i values, then the full likelihood function is obtained simply by multiplying the original one by a Gaussian, and so when we find the new χ^2 from $-2\ln L$ there is an additional term, namely,

$$\chi^2(\boldsymbol{\theta}) = \sum_{i=1}^{n} \frac{(y_i - \mu(x_i;\boldsymbol{\theta}))^2}{\sigma_i^2} + \frac{(\theta_1 - t_1)^2}{\sigma_{t_1}^2} \; . \tag{11}$$

As shown in Fig. 2(b), the new (solid) contour of $\chi^2 = \chi^2_{\rm min} + 1$ is compressed relative to the old (dashed) one in the θ_1 direction, and this compression has the effect of decreasing the error in θ_0 as well. The lesson is: by better constraining nuisance parameters, one improves the statistical accuracy of the parameters of interest.

2.2.2 The Bayesian approach

To treat the example above in the Bayesian framework, we write Bayes' theorem (2) as

$$p(\boldsymbol{\theta}|\mathbf{y}) = \frac{L(\mathbf{y}|\boldsymbol{\theta})\pi(\boldsymbol{\theta})}{\int L(\mathbf{y}|\boldsymbol{\theta})\pi(\boldsymbol{\theta})\, d\boldsymbol{\theta}} \; . \tag{12}$$

Here $\boldsymbol{\theta} = (\theta_0, \theta_1)$ symbolizes the hypothesis whose probability we want to determine. The likelihood $L(\mathbf{y}|\boldsymbol{\theta})$ is the probability to obtain the data $\mathbf{y} = (y_1, \ldots, y_n)$ given the hypothesis, and the prior probability $\pi(\boldsymbol{\theta}|\mathbf{y})$ represents our degree of belief about the parameters before seeing the outcome of the experiment. The posterior probability $p(\boldsymbol{\theta})$ encapsulates all of our knowledge about $\boldsymbol{\theta}$ when the data $\mathbf{y}$ is combined with our prior beliefs. The denominator in (12) serves to normalize the posterior pdf to unit area.

The likelihood $L(\mathbf{y}|\boldsymbol{\theta})$ is the same as the $L(\boldsymbol{\theta})$ that we used in the frequentist approach above. The slightly different notation here simply emphasizes its role as the conditional probability for the data given the parameter.

To proceed we need to write down a prior probability density $\pi(\theta_0, \theta_1)$. This phase of a Bayesian analysis, sometimes called the *elicitation of expert opinion*, is in many ways the most problematic, as there are no universally accepted rules to follow. Here we will explore some of the important issues that come up.

In general, prior knowledge about one parameter might affect knowledge about the other, and if so this must be built into $\pi(\theta_0, \theta_1)$. Often, however, one may regard the prior knowledge about the parameters as independent, in which case the density factorizes as

$$\pi(\theta_0, \theta_1) = \pi_0(\theta_0)\pi_1(\theta_1) \ . \tag{13}$$

For purposes of the present example we will assume that this holds.

For the parameter of interest θ_0, it may be that we have essentially no prior information, so the density $\pi_0(\theta_0)$ should be very broad. Often one takes the limiting case of a broad distribution simply to be a constant, i.e.,

$$\pi_0(\theta_0) = \text{const.} \ . \tag{14}$$

Now one apparent problem with Eq. (14) is that it is not normalizable to unit area, and so does not appear to be a valid probability density. It is said to be an *improper prior*. The prior always appears in Bayes' theorem multiplied by the likelihood, however, and as long as this falls off quickly enough as a function of the parameters, then the resulting posterior probability density can be normalized to unit area.

A further problem with uniform priors is that if the prior pdf is flat in $\boldsymbol{\theta}$, then it is not flat for a nonlinear function of $\boldsymbol{\theta}$, and so a different parametrization of the problem would lead in general to a non-equivalent posterior pdf.

For the special case of a constant prior, one can see from Bayes' theorem (12) that the posterior is proportional to the likelihood, and therefore the mode (peak position) of the posterior is equal to the ML estimator. The posterior mode, however, will change in general upon a transformation of parameter. A summary statistic other than the mode may be used as the Bayesian estimator, such as the median, which is invariant under parameter transformation. But this will not in general coincide with the ML estimator.

For the prior $\pi_1(\theta_1)$, let us assume that our prior knowledge about this parameter includes the earlier measurement t_1, which we modelled as a Gaussian distributed variable centred about θ_1 with standard deviation σ_{t_1}. If we had taken, even prior to that measurement, a constant prior for θ_1, then the "intermediate-state" prior that we have before looking at the y_i is simply this flat prior times the Gaussian likelihood, i.e., a Gaussian prior in θ_1:

$$\pi_1(\theta_1) = \frac{1}{\sqrt{2\pi}\sigma_{t_1}} e^{-(\theta_1 - t_1)^2/2\sigma_{t_1}^2} \ . \tag{15}$$

Putting all of these ingredients into Bayes' theorem gives

$$p(\theta_0, \theta_1|\mathbf{y}) \propto \prod_{i=1}^{n} \frac{1}{\sqrt{2\pi}\sigma_i} e^{-(y_i - \mu(x_i;\theta_0,\theta_1))^2/2\sigma_i^2} \, \pi_0 \, \frac{1}{\sqrt{2\pi}\sigma_{t_1}} e^{-(\theta_1 - t_1)^2/2\sigma_{t_1}^2} \ , \tag{16}$$

where π_0 represents the constant prior in θ_0 and the equation has been written as a proportionality with the understanding that the final posterior pdf should be normalized to unit area.

What Bayes' theorem gives us is the full joint pdf $p(\theta_0, \theta_1|\mathbf{y})$ for both the parameter of interest θ_0 as well as the nuisance parameter θ_1. To find the pdf for the parameter of interest only, we simply integrate (marginalize) the joint pdf, i.e.,

$$p(\theta_0|\mathbf{y}) = \int p(\theta_0, \theta_1|\mathbf{y})\, d\theta_1 \ . \tag{17}$$

In this example, it turns out that we can do the integral in closed form. We find a Gaussian posterior,

$$p(\theta_0|\mathbf{y}) = \frac{1}{\sqrt{2\pi}\sigma_{\theta_0}} e^{-(\theta_0-\hat{\theta}_0)^2/2\sigma^2_{\theta_0}} \ , \tag{18}$$

where $\hat{\theta}_0$ is in fact the same as the ML (or LS) estimator found above with the frequentist approach, and σ_{θ_0} is the same as the standard deviation of that estimator $\sigma_{\hat{\theta}_0}$.

So we find something that looks just like the frequentist answer, although here the interpretation of the result is different. The posterior pdf $p(\theta_0|\mathbf{y})$ gives our degree of belief about the location of the parameter in the light of the data. We will see below how the Bayesian approach can, however, lead to results that differ both in interpretation as well as in numerical value from what would be obtained in a frequentist calculation. First, however, we need to pause for a short digression on Bayesian computation.

2.2.3 Bayesian computation and MCMC

In most real Bayesian calculations, the marginalization integrals cannot be carried out in closed form, and if the number of nuisance parameters is too large then they can also be difficult to compute with standard Monte Carlo methods. However, *Markov Chain Monte Carlo* (MCMC) has become the most important tool for computing integrals of this type and has revolutionized Bayesian computation. In depth treatments of MCMC can be found, e.g., in the texts by Robert and Casella [9], Liu [10], and the review by Neal [11].

The basic idea behind using MCMC to marginalize the joint pdf $p(\theta_0, \theta_1|\mathbf{y})$ is to sample points $\boldsymbol{\theta} = (\theta_0, \theta_0)$ according to the posterior pdf but then only to look at the distribution of the component of interest, θ_0. A simple and widely applicable MCMC method is the Metropolis-Hastings algorithm, which allows one to generate multidimensional points $\boldsymbol{\theta}$ distributed according to a target pdf that is proportional to a given function $p(\boldsymbol{\theta})$, which here will represent our posterior pdf. It is not necessary to have $p(\boldsymbol{\theta})$ normalized to unit area, which is useful in Bayesian statistics, as posterior probability densities are often determined only up to an unknown normalization constant, as is the case in our example.

To generate points that follow $p(\boldsymbol{\theta})$, one first needs a proposal pdf $q(\boldsymbol{\theta}; \boldsymbol{\theta}_0)$, which can be (almost) any pdf from which independent random values $\boldsymbol{\theta}$ can be generated, and which contains as a parameter another point in the same space $\boldsymbol{\theta}_0$. For example, a multivariate Gaussian centred about $\boldsymbol{\theta}_0$ can be used. Beginning at an arbitrary starting point $\boldsymbol{\theta}_0$, the Hastings algorithm iterates the following steps:

1. Generate a value $\boldsymbol{\theta}$ using the proposal density $q(\boldsymbol{\theta}; \boldsymbol{\theta}_0)$;
2. Form the Hastings test ratio, $\alpha = \min\left[1, \frac{p(\boldsymbol{\theta})q(\boldsymbol{\theta}_0;\boldsymbol{\theta})}{p(\boldsymbol{\theta}_0)q(\boldsymbol{\theta};\boldsymbol{\theta}_0)}\right]$;
3. Generate a value u uniformly distributed in $[0, 1]$;
4. If $u \leq \alpha$, take $\boldsymbol{\theta}_1 = \boldsymbol{\theta}$. Otherwise, repeat the old point, i.e., $\boldsymbol{\theta}_1 = \boldsymbol{\theta}_0$.

If one takes the proposal density to be symmetric in $\boldsymbol{\theta}$ and $\boldsymbol{\theta}_0$, then this is the *Metropolis*-Hastings algorithm, and the test ratio becomes $\alpha = \min[1, p(\boldsymbol{\theta})/p(\boldsymbol{\theta}_0)]$. That is, if the proposed $\boldsymbol{\theta}$ is at a value of probability higher than $\boldsymbol{\theta}_0$, the step is taken. If the proposed step is rejected, hop in place.

Methods for assessing and optimizing the performance of the algorithm are discussed in, e.g., [9, 10, 11]. One can, for example, examine the autocorrelation as a function of the lag k, i.e., the correlation of a sampled point with one k steps removed. This should decrease as quickly as possible for increasing k. Generally one chooses the proposal density so as to optimize some quality measure such as the autocorrelation. For certain problems it has been shown that one achieves optimal performance

when the acceptance fraction, that is, the fraction of points with $u \leq \alpha$, is around 40%. This can be adjusted by varying the width of the proposal density. For example, one can use for the proposal pdf a multivariate Gaussian with the same covariance matrix as that of the target pdf, but scaled by a constant.

For our example above, MCMC was used to generate points according to the posterior pdf $p(\theta_0, \theta_1)$ by using a Gaussian proposal density. The result is shown in Fig. 3.

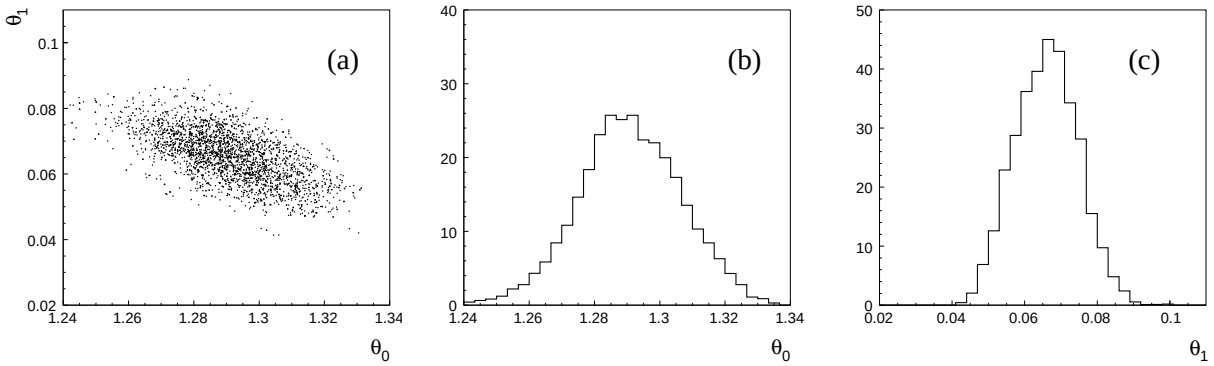

Fig. 3: MCMC marginalization of the posterior pdf $p(\theta_0, \theta_1|\mathbf{y})$: (a) scatter-plot of points in (θ_0, θ_1) plane and the marginal distribution of (a) the parameter of interest θ_0 and (b) the nuisance parameter θ_1.

From the (θ_0, θ_1) points in the scatter plot in Fig. 3(a) we simply look at the distribution of the parameter of interest, θ_0 (Fig. 3(b)). The standard deviation of this distribution is what we would report as the statistical error in our measurement of θ_0. The distribution of the nuisance parameter θ_1 from Fig. 3(c) is not directly needed, although it may be of interest in some other context where that parameter is deemed interesting.

In fact one can go beyond simply summarizing the width of the distributions with the a statistic such as the standard deviation. The full form of the posterior distribution of θ_0 contains useful information about where the parameter's true value is likely to be. In this example the distributions will in fact turn out to be Gaussian, but in a more complex analysis there could be non-Gaussian tails and this information can be relevant in drawing conclusions from the result.

2.2.4 Sensitivity analysis

The posterior distribution of θ_0 obtained above encapsulates all of the analyst's knowledge about the parameter in the light of the data, given that the prior beliefs were reflected by the density $\pi(\theta_0, \theta_1)$. A different analyst with different prior beliefs would in general obtain a different posterior pdf. We would like the result of a Bayesian analysis to be of value to the broader scientific community, not only to those that share the prior beliefs of the analyst. And therefore it is important in a Bayesian analysis to show by how much the posterior probabilities would change upon some reasonable variation in the prior. This is sometimes called the *sensitivity analysis* and is an important part of any Bayesian calculation.

In the example above, we can imagine a situation where there was no prior measurement t_1 of the parameter θ_1, but rather a theorist had told us that, based on considerations of symmetry, consistency, aesthetics, etc., that θ_1 was "almost certainly" positive, and had a magnitude "probably less than 0.1 or so". When pressed to be precise, the theorist sketches a curve roughly resembling an exponential with a mean of 0.1. So we can express this prior as

$$\pi_1(\theta_1) = \frac{1}{\tau} e^{-\theta_1/\tau} \quad (\theta_1 \geq 0) \,, \tag{19}$$

with $\tau \approx 0.1$. We can substitute this prior into Bayes' theorem (16) to obtain the joint pdf for θ_0 and θ_1, and then marginalize to find the pdf for θ_0. Doing this numerically with MCMC results in the posterior

distributions shown in Fig. 4(a).

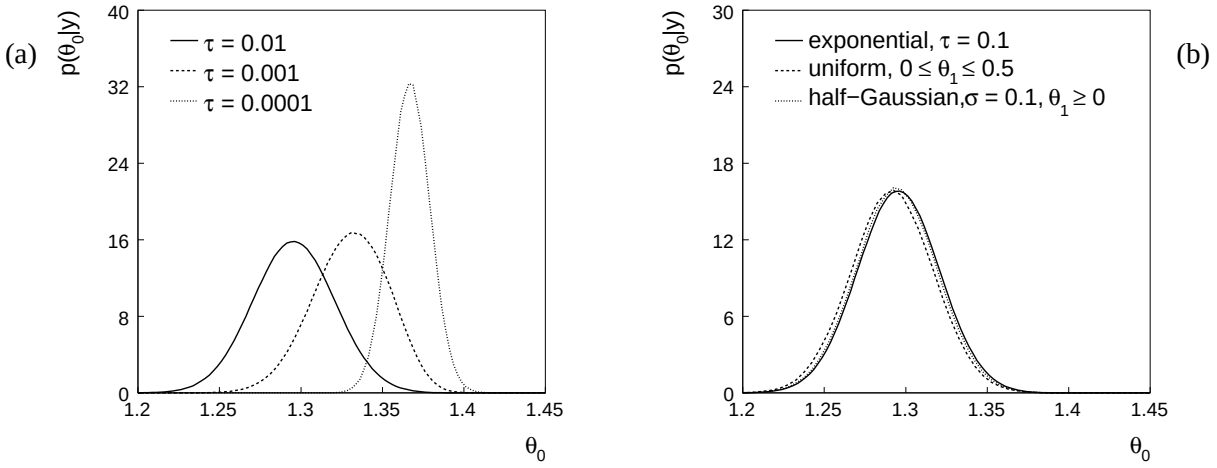

Fig. 4: Posterior probability densities for the parameter θ_0 obtained using (a) an exponential prior for θ_0 of different widths and (b) several different functional forms for the prior.

Now the theorist who proposed this prior for θ_1 may feel reluctant to be pinned down, and it so it is important to recall (and to reassure the theorist about) the "if-then" nature of a Bayesian analysis. One does not have to be absolutely certain about the prior in Eq. (19). Rather, Bayes' theorem simply says that *if* one were to have these prior beliefs, *then* we obtain certain posterior beliefs in the light of the data.

One simple way to vary the prior here is to try different values of the mean τ, as shown in Fig. 4(a). We see here the same basic feature as shown already in the frequentist analysis, namely, that when one increases the precision about the nuisance parameter, θ_1, then the knowledge about the parameter of interest, θ_0, is improved.

Alternatively (or in addition) we may try different functional forms for the prior, as shown in Fig. 4(b). In this case using a uniform distribution for $\pi_1(\theta_1)$ with $0 \leq \theta_1 \leq 0.5$ or Gaussian with $\sigma = 0.1$ truncated for $\theta_1 < 0$ both give results similar to the exponential with a mean of 0.1. So one concludes that the result is relatively insensitive to the detailed nature of the tails of $\pi_1(\theta_1)$.

2.3 A fit with systematic errors

We can now generalize the example of Sec. 2.2 to explore some further aspects of a Bayesian analysis. Let us suppose that we are given a set of n measurements as above, but now in addition to the statistical errors we also are given systematic errors. That is, we are given $y_i \pm \sigma_i^{\rm stat} \pm \sigma_i^{\rm sys}$ for $i = 1, \ldots, n$ where the measurements as before are each carried out for a specified value of a control variable x.

More generally, instead of having $y_i \pm \sigma_i^{\rm stat} \pm \sigma_i^{\rm sys}$ it may be that the set of measurements comes with an $n \times n$ covariance matrix $V^{\rm stat}$ corresponding to the statistical errors and another matrix $V^{\rm sys}$ for the systematic ones. Here the square roots of the diagonal elements give the errors for each measurement, and the off-diagonal elements provide information on how they are correlated.

As before we assume some functional form $\mu(x; \boldsymbol{\theta})$ for the expectation values of the y_i. This could be the linear model of Eq. (6) or something more general, but in any case it depends on a vector of unknown parameters $\boldsymbol{\theta}$. In this example, however, we will allow that the model is not perfect, but rather could have a systematic bias. That is, we write the true expectation value of the ith measurement can be written

$$E[y_i] = \mu(x_i; \boldsymbol{\theta}) + b_i \ , \tag{20}$$

where b_i represents the bias. The b_i can be viewed as the systematic errors of the model, present even when the parameters $\boldsymbol{\theta}$ are adjusted to give the best description of the data. We do not know the values of the b_i. If we did, we would account for them in the model and they would no longer be biases. We do not in fact know that their values are nonzero, but we are allowing for the possibility that they could be. The reported systematic errors are intended as a quantitative measure of how large the we expect the biases to be.

As before, the goal is to make inferences about the parameters $\boldsymbol{\theta}$; some of these may be of direct interest and others may be nuisance parameters. In Sec. 2.3.1 we will try to do this using the frequentist approach, and in Sec. 2.3.2 we will use the Bayesian method.

2.3.1 A frequentist fit with systematic errors

If we adopt the frequentist approach, we need to write down a likelihood function such as Eq. 8, but here we know in advance that the model $\mu(x;\boldsymbol{\theta})$ is not expected to be fully accurate. Furthermore it is not clear how to insert the systematic errors. Often, perhaps without a clear justification, one simply adds the statistical and systematic errors in quadrature, or in the case where one has the covariance matrices $V^{\rm stat}$ and $V^{\rm sys}$, they are summed to give a sort of "full" covariance matrix:

$$V_{ij} = V_{ij}^{\rm stat} + V_{ij}^{\rm sys} \; . \tag{21}$$

One might then use this in a multivariate Gaussian likelihood function, or equivalently it could be used to construct the χ^2,

$$\chi^2(\boldsymbol{\theta}) = (\mathbf{y} - \boldsymbol{\mu}(\boldsymbol{\theta}))^T V^{-1} (\mathbf{y} - \boldsymbol{\mu}(\boldsymbol{\theta})) \; , \tag{22}$$

which is then minimized to find the LS estimators for $\boldsymbol{\theta}$. In Eq. (22) the vector $\mathbf{y} = (y_1, \ldots, y_n)$ should be understood as a column vector, $\boldsymbol{\mu}(\boldsymbol{\theta}) = (\mu(x_1;\boldsymbol{\theta}), \ldots, \mu(x_n;\boldsymbol{\theta}))$ is the corresponding vector of model values, and the superscript T represents the transpose (row) vector. Minimizing this χ^2 gives the generalized LS estimators $\hat{\boldsymbol{\theta}}$, and the usual procedures can be applied to find their covariances, which now in some sense include the systematics.

But in what sense is there any formal justification for adding the covariance matrices in Eq. (21)? Next we will treat this problem in the Bayesian framework and see that there is indeed some reason behind this recipe, but with limitations, and further we will see how to get around these limitations.

2.3.2 The equivalent Bayesian fit

In the corresponding Bayesian analysis, one treats the statistical errors as given by $V^{\rm stat}$ as reflecting the distribution of the data $\mathbf{y}$ in the likelihood. The systematic errors, through $V^{\rm sys}$, reflect the width of the prior probabilities for the bias parameters b_i. That is, we take

$$L(\mathbf{y}|\boldsymbol{\theta},\mathbf{b}) \;\propto\; \exp\left[-\tfrac{1}{2}(\mathbf{y} - \boldsymbol{\mu}(\boldsymbol{\theta}) - \mathbf{b})^T V_{\rm stat}^{-1} (\mathbf{y} - \boldsymbol{\mu}(\boldsymbol{\theta}) - \mathbf{b})\right] \; , \tag{23}$$

$$\pi_b(\mathbf{b}) \;\propto\; \exp\left[-\tfrac{1}{2}\mathbf{b}^T V_{\rm sys}^{-1} \mathbf{b}\right] \; , \qquad \pi_\theta(\boldsymbol{\theta}) = \text{const.} \; , \tag{24}$$

$$p(\boldsymbol{\theta},\mathbf{b}|\mathbf{y}) \;\propto\; L(\mathbf{y}|\boldsymbol{\theta},\mathbf{b})\pi_\theta(\boldsymbol{\theta})\pi_b(\mathbf{b}) \; , \tag{25}$$

where in (25), Bayes' theorem is used to obtain the joint probability for the parameters of interest, $\boldsymbol{\theta}$, and also the biases $\mathbf{b}$. To obtain the probability for $\boldsymbol{\theta}$ we integrate (marginalize) over $\mathbf{b}$,

$$p(\boldsymbol{\theta}|\mathbf{y}) = \int p(\boldsymbol{\theta},\mathbf{b}|\mathbf{y})\, d\mathbf{b} \; . \tag{26}$$

One finds that the mode of $p(\boldsymbol{\theta}|\mathbf{y})$ is at the same position as the least-squares estimates, and its covariance will be the same as obtained from the frequentist analysis where the full covariance matrix was given by the sum $V = V^{\rm stat} + V^{\rm sys}$. So this can be taken in effect as the formal justification for the addition in quadrature of statistical and systematic errors in a Least Squares fit.

2.3.3 The error on the error

If one stays with the prior probabilities used above, the Bayesian and least-squares approaches deliver essentially the same result. An advantage of the Bayesian framework, however, is that it allows one to refine the assessment of the systematic uncertainties as expressed through the prior probabilities.

For example, the least-squares fit including systematic errors is equivalent to the assumption of a Gaussian prior for the biases. A more realistic prior would take into account the experimenters own uncertainty in assigning the systematic error, i.e., the 'error on the error'. Suppose, for example, that the ith measurement is characterized by a reported systematic uncertainty $\sigma_i^{\rm sys}$ and an unreported factor s_i, such that the prior for the bias b_i is

$$\pi_b(b_i) = \int \frac{1}{\sqrt{2}\pi\sigma_i^{\rm sys}} \exp\left[-\frac{1}{2}\frac{b_i^2}{(s_i\sigma_i^{\rm sys})^2}\right] \pi_s(s_i)\, ds_i \ . \tag{27}$$

Here the 'error on the error' is encapsulated in the prior for the factor s, $\pi_s(s)$. For this we can take whatever function is deemed appropriate. For some types of systematic error it could be close to the ideal case of a delta function centred about unity. Many reported systematics are, however, at best rough guesses, and one could easily imagine a function $\pi_s(s)$ with a mean of unity but a standard deviation of, say, 0.5 or more. Here we show examples using a Gamma distribution for $\pi_s(s)$, which results in substantially longer tails for the prior $\pi_b(b)$ than those of the Gaussian. This can be seen in Fig. 5(a), which shows $\ln \pi_b(b)$ for different values of the standard deviation of $\pi_s(s)$, σ_s. Related studies using an inverse Gamma distribution can be found in [12, 13], which have the advantage that the posterior pdf can be written down in closed form.

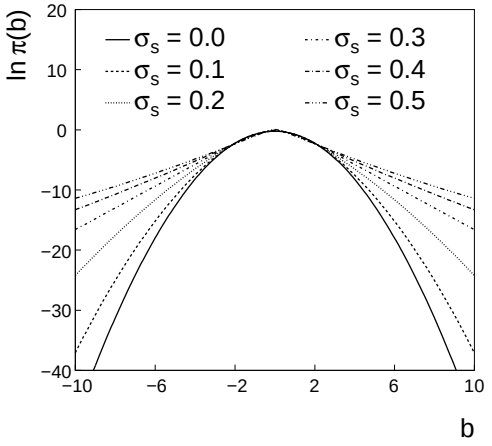

Fig. 5: The log of the prior pdf for a bias parameter b for different values of the standard deviation of $\pi_s(s)$.

Using a prior for the biases with tails longer than those of a Gaussian results in a reduced sensitivity to outliers, which arise when an experimenter overlooks an important source of systematic uncertainty in the estimated error of a measurement. As a simple test of this, consider the sample data shown in Fig. 6(a). Suppose these represent four independent measurements of the same quantity, here a parameter called μ, and the goal is to combine the measurements to provide a single estimate of μ. That is, we are effectively fitting a horizontal line to the set of measured y values, where the control variable x is just a label for the measurements.

In this example, suppose that each measurement y_i, $i = 1, \ldots 4$, is modelled as Gaussian distributed about μ, having a a standard deviation $\sigma_{\rm stat} = 0.1$, and furthermore each measurement has a systematic uncertainty $\sigma_{\rm sys} = 0.1$, which here is taken to refer to the standard deviation of the Gaussian component of the prior $\pi_b(b_i)$. This is then folded together with $\pi_s(s_i)$ to get the full prior for b_i using Eq. (27), and the joint prior for the vector of bias parameters is simply the product of the corresponding terms, as the systematic errors here are treated as being independent. These ingredients are then assembled according to the recipe of Eqs. (23)–(26) to produce the posterior pdf for μ, $p(\mu|\mathbf{y})$.

Results of the exercise are shown in Fig. 6. In Fig. 6(a), the four measurements y_i are reasonably consistent with each other. Figure 6(b) shows the corresponding posterior $p(\mu|\mathbf{y})$ for two values of σ_s, which reflect differing degrees of non-Gaussian tails in the prior for the bias parameters, $\pi_b(b_i)$. For $\sigma_s = 0$, the prior for the bias is exactly Gaussian, whereas for $\sigma_s = 0.5$, the non-Gaussian tails are considerably longer, as can be seen from the corresponding curves in Fig. 5(a). The posterior pdfs for both cases are almost identical, as can be see in Fig. 6(a). Determining the mean and standard deviation of the posterior for each gives $\hat{\mu} = 1.000 \pm 0.71$ for the case of $\sigma_s = 0$, and $\hat{\mu} = 1.000 \pm 0.72$ for $\sigma_s = 0.5$. So assuming a 50% "error on the error" here has only inflates the error of the averaged result by a small amount.

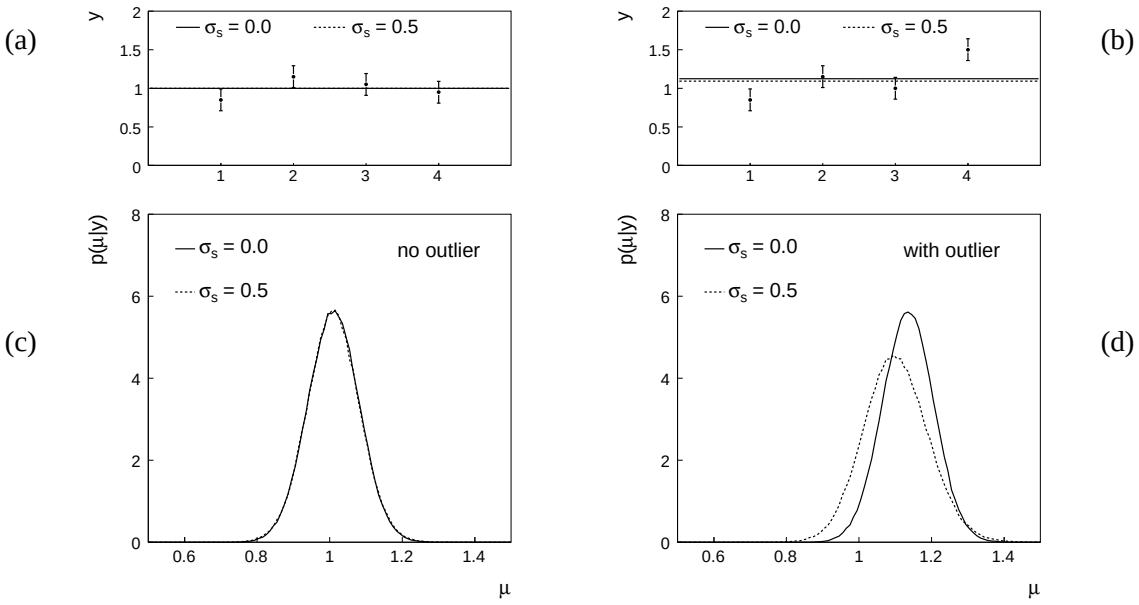

Fig. 6: (a) Data values which are relatively consistent and (b) a data set with an outlier; the horizontal lines indicate the posterior mean for two different values of the parameter σ_s. (c) and (d) show the posterior distributions corresponding to (a) and (b), respectively. (The dashed and solid curves in (a) and (c) overlap.)

Now consider the case where one of the measured values is substantially different from the other three, as shown in Fig. 6(c). Here using the same priors for the bias parameters results in the posteriors shown in Fig. 6(d). The posterior means and standard deviations are $\hat{\mu} = 1.125 \pm 0.71$ for the case of $\sigma_s = 0$, and $\hat{\mu} = 1.093 \pm 0.089$ for $\sigma_s = 0.5$.

When we assume a purely Gaussian prior for the bias ($\sigma_s = 0.0$), the presence of the outlier has in fact no effect on the width of the posterior. This is rather counter-intuitive and results from our assumption of a Gaussian likelihood for the data and a Gaussian prior for the bias parameters. The posterior mean is however pulled substantially higher than the three other measurements, which are clustered around 1.0. If the priors $\pi_b(b_i)$ have longer tails, as occurs when we take $\sigma_s = 0.5$, then the posterior is broader, and furthermore it is pulled less far by the outlier, as can be seen in Fig. 6(d).

The fact that the width of the posterior distribution, which effectively tells us the uncertainty on the parameter of interest μ, becomes coupled to the internal consistency of the data. In contrast, in the (frequentist) Least-Squares method, or in the Bayesian approach using a Gaussian prior for the bias parameters, the final uncertainty on the parameter of interest is unaffected by the presence of outliers. And in many cases of practical interest, it would be in fact appropriate to conclude that the presence of outliers should indeed increase one's uncertainty about the final parameter estimates. The example shown here can be generalized to cover a wide variety of model uncertainties by including prior probabilities for an enlarged set of model parameters.

2.4 Summary on Bayesian methods

In these lectures we have seen how Bayesian methods can be used in parameter estimation, and this has also given us the opportunity to discuss some aspects of Bayesian computation, including the important tool of Markov Chain Monte Carlo. Although Bayesian and frequentist methods may often deliver results that agree numerically, there is an important difference in their interpretation. Furthermore, Bayesian methods allow one to incorporate prior information that may be based not on other measurements but rather on theoretical arguments or purely subjective considerations. And as these considerations may not find universal agreement, it is important to investigate how the results of a Bayesian analysis would change for a reasonable variation of the prior probabilities.

It is important to keep in mind that in the Bayesian approach, all information about the parameters is encapsulated in the posterior probabilities. So if the analyst also wants to set upper limits or determine intervals that cover the parameter with a specified probability, then this is a straightforward matter of finding the parameter limits such that the integrated posterior pdf has the desired probability content. A discussion of Bayesian methods to the important problem of setting upper limits on a Poisson parameter are covered in [1] and references therein; we will not have time in these lectures to go into that question here.

We will also unfortunately not have time to explore Bayesian model selection. This allows one to quantify the degree to which the the data prefer one model over the other using a quantity called the Bayes factor. These have not yet been widely used in particle physics but should be kept in mind as providing important complementary information to the corresponding outputs of Frequentist hypothesis testing such as p-values. A brief description of Bayes factors can be found in Ref. [1] and a more in-depth treatment is given in Ref. [14].

3 Topics in multivariate analysis

In the second part of these lectures we will take a look at the important topic of multivariate analysis. In depth information on this topic can be found in the textbooks [15, 16, 17, 18]. In a particle physics context, multivariate methods are often used when selecting events of a certain type using some potentially large number of measurable characteristics for each event. The basic framework we will use to examine these methods is that of a frequentist hypothesis test.

The fundamental unit of data in a particle physics experiment is the "event", which in most cases corresponds to a single particle collision. In some cases it could be instead a decay, and the picture does not change much if we look, say, at individual particles or tracks. But to be concrete let us suppose that we want to search for events from proton-proton collisions at the LHC that correspond to some interesting "signal" process, such as supersymmetry.

When running at full intensity, the LHC should produce close to a billion events per second. After a quick sifting, the data from around 200 per second are recorded for further study, resulting in more than a billion events per year. But only a tiny fraction of these are of potential interest. If one of the speculative theories such as supersymmetry turns out to be realized in Nature, then this will result in a subset of events having characteristic features, and the SUSY events will simply be mixed in randomly

with a much larger number of Standard Model events. The relevant distinguishing features depend on what new physics Nature chooses to reveal, but one might see, for example, high $p_{\rm T}$ jets, leptons, missing energy, etc.

Unfortunately, background processes (e.g., Standard model events) can often mimic these features and one will not be able to say with certainty that a given event shows a clear evidence for something new such as supersymmetry. For example, even Standard Model events can contain neutrinos which also escape undetected. The typical amount and pattern of missing energy in these events differs on average, however, from what a SUSY event would give, and so a statistical analysis can be applied to test whether something besides Standard Model events are present.

In a typical analysis there is a class of event we are interested in finding (signal), and these, if they exist at all, are mixed in with the rest of the events (background). The data for each event is some collection of numbers $\mathbf{x} = (x_1, \ldots, x_n)$ representing particle energies, momenta, etc. We will refer to these as the *input variables* of the problem. And the probabilities are joint densities for $\mathbf{x}$ given the signal (s) or background (b) hypotheses: $f(\mathbf{x}|\mathrm{s})$ and $f(\mathbf{x}|\mathrm{b})$.

To illustrate the general problem, consider the scatterplots shown in Fig. 7. These show the distribution of two variables, x_1 and x_2, which represent two out of a potentially large number of quantities measured for each event. The blue circles could represent the sought after signal events, and the red triangles the background. In each of the three figures there is a decision boundary representing a possible way of classifying the events.

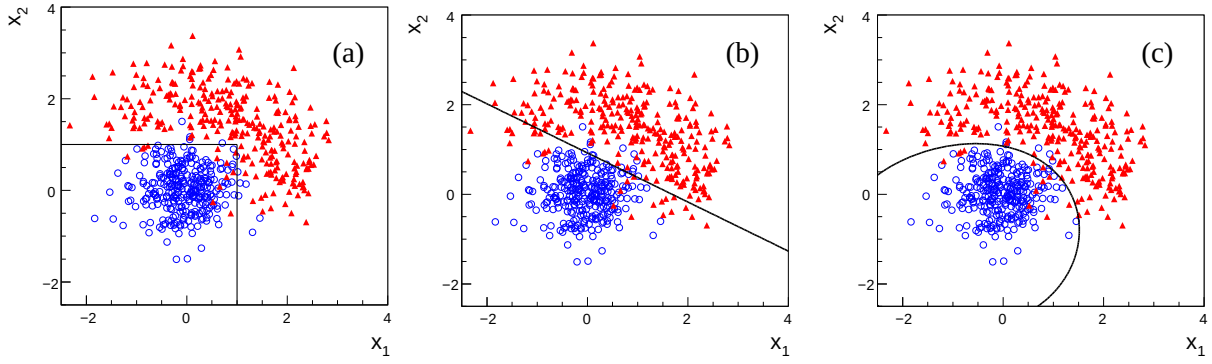

Fig. 7: Scatter plots of two variables corresponding to two hypotheses: signal and background. Event selection could be based, e.g., on (a) cuts, (b) a linear boundary, (c) a nonlinear boundary.

Figure 7(a) represents what is commonly called the "cut-based" approach. One selects signal events by requiring $x_1 < c_1$ and $x_2 < c_2$ for some suitably chosen cut values c_1 and c_2. If x_1 and x_2 represent quantities for which one has some intuitive understanding, then this can help guide one's choice of the cut values.

Another possible decision boundary is made with a diagonal cut as shown in Fig. 7(b). One can show that for certain problems a linear boundary has optimal properties, but in the example here, because of the curved nature of the distributions, neither the cut-based nor the linear solution is as good as the nonlinear boundary shown in Fig. 7(c).

The decision boundary is a surface in the n-dimensional space of input variables, which can be represented by an equation of the form $y(\mathbf{x}) = y_{\rm cut}$, where $y_{\rm cut}$ is some constant. We accept events as corresponding to the signal hypothesis if they are on one side of the boundary, e.g., $y(\mathbf{x}) \leq y_{\rm cut}$ could represent the acceptance region and $y(\mathbf{x}) > y_{\rm cut}$ could be the rejection region.

Equivalently we can use the function $y(\mathbf{x})$ as a scalar *test statistic*. Once its functional form is specified, we can determine the pdfs of $y(\mathbf{x})$ under both the signal and background hypotheses, $p(y|\mathrm{s})$ and $p(y|\mathrm{b})$. The decision boundary is now effectively a single cut on the scalar variable y, as illustrated

in Fig. 8.

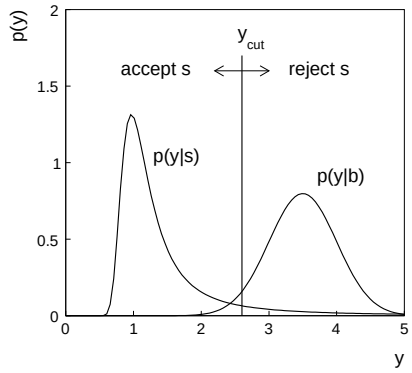

Fig. 8: Distributions of the scalar test statistic $y(\mathbf{x})$ under the signal and background hypotheses.

To quantify how good the event selection is, we can define the *efficiency* with which one selects events of a given type as the probability that an event will fall in the acceptance region. That is, the signal and background efficiencies are

$$\varepsilon_{\rm s} \;=\; P(\text{accept event}|\text{s}) = \int_{\rm A} f(\mathbf{x}|\text{s})\, d\mathbf{x} = \int_{-\infty}^{y_{\rm cut}} p(y|\text{s})\, dy \;, \tag{28}$$

$$\varepsilon_{\rm b} \;=\; P(\text{accept event}|\text{b}) = \int_{\rm A} f(\mathbf{x}|\text{b})\, d\mathbf{x} = \int_{y_{\rm cut}}^{\infty} p(y|\text{b})\, dy \;, \tag{29}$$

where the region of integration A represents the acceptance-region.

Dividing the space of input variables into two regions where one accepts or rejects the signal hypothesis is essentially the language of a frequentist statistical test. If we regard background as the "null hypothesis", then the background efficiency is the same as what in a statistical context would be called the significance level of the test, or the rate of "type-I errors". Viewing the signal process as the alternative, the signal efficiency is then what a statistician would call the power of the test; it is the probability to reject the background hypothesis if in fact the signal hypothesis is true. Equivalently, this is one minus the rate of "type-II error".

The use of a statistical test to distinguish between two classes of events (signal and background), comes up in different ways. Sometimes both event classes are known to exist, and the goal is to select one class (signal) for further study. For example, proton-proton collisions leading to the production of top quarks are a well-established process. By selecting these events one can carry out precise measurements of the top quark's properties such as its mass. In other cases, the signal process could represent an extension to the Standard Model, say, supersymmetry, whose existence is not yet established, and the goal of the analysis is to see if one can do this. Rejecting the Standard Model with a sufficiently high significance level amounts to discovering something new, and of course one hopes that the newly revealed phenomena will provide important insights into how Nature behaves.

What the physicist would like to have is a test with maximal power with respect to a broad class of alternative hypotheses. For two specific signal and background hypotheses, it turns out that there is a well defined optimal solution to our problem. The *Neyman–Pearson* lemma states that one obtains the maximum power relative for the signal hypothesis for a given significance level (background efficiency) by defining the acceptance region such that, for $\mathbf{x}$ inside the region, the *likelihood ratio*, i.e., the ratio of pdfs for signal and background,

$$\lambda(\mathbf{x}) = \frac{f(\mathbf{x}|\text{s})}{f(\mathbf{x}|\text{b})} \;, \tag{30}$$

is greater than or equal to a given constant, and it is less than this constant everywhere outside the acceptance region. This is equivalent to the statement that the ratio (30) represents the test statistic with which one obtains the highest signal efficiency for a given background efficiency, or equivalently, for a given signal purity.

In principle the signal and background theories should allow us to work out the required functions $f(\mathbf{x}|\mathrm{s})$ and $f(\mathbf{x}|\mathrm{b})$, but in practice the calculations are too difficult and we do not have explicit formulae for these. What we have instead of $f(\mathbf{x}|\mathrm{s})$ and $f(\mathbf{x}|\mathrm{b})$ are complicated Monte Carlo programs, that is, we can sample $\mathbf{x}$ to produce simulated signal and background events. Because of the multivariate nature of the data, where $\mathbf{x}$ may contain at least several or perhaps even hundreds of components, it is a nontrivial problem to construct a test with a power approaching that of the likelihood ratio.

In the usual case where the likelihood ratio (30) cannot be used explicitly, there exists a variety of other multivariate classifiers that effectively separate different types of events. Methods often used in HEP include *neural networks* or *Fisher discriminants*. Recently, further classification methods from machine-learning have been applied in HEP analyses; these include *probability density estimation (PDE)* techniques, *kernel-based PDE* (*KDE* or *Parzen window*), *support vector machines*, and *decision trees*. Techniques such as "boosting" and "bagging" can be applied to combine a number of classifiers into a stronger one with greater stability with respect to fluctuations in the training data. Descriptions of these methods can be found in, e.g., the textbooks [15, 16, 17, 18] and in Proceedings of the PHYSTAT conference series [19]. Software for HEP includes the `TMVA` [20] and `StatPatternRecognition` [21] packages, although support for the latter has unfortunately been discontinued.

As we will not have the time to examine all of the methods mentioned above, in the following section we look at a specific example of a classifier to illustrate some of the main ideas of a multivariate analysis: the boosted decision tree (BDT).

3.1 Boosted decision trees

Boosted decision trees exploit relatively recent developments in machine learning and have gained significant popularity in HEP. First in Sec. 3.1.1 we describe the basic idea of a decision tree, and then in Sec. 3.1.2 we will say how the the technique of "boosting" can be used to improve its performance.

3.1.1 Decision trees

A decision tree is defined by a collection of successive cuts on the set of input variables. To determine the appropriate cuts, one begins with a sample of N training events which are known to be either signal or background., e.g., from Monte Carlo. The set of n input variables measured for each event constitutes a vector $\mathbf{x} = (x_1, \ldots x_n)$. Thus we have N instances of $\mathbf{x}$, $\mathbf{x}_1, \ldots \mathbf{x}_N$, as well as the corresponding N true class labels $y_1, \ldots, y_N$. It is convenient to assign numerical values to the labels so that, e.g., $y = 1$ corresponds to signal and $y = -1$ for background.

In addition we will assume that each event can be assigned a weight, w_i, with $i = 1, \ldots, N$. For any subset of the events and for a set of weights, the signal fraction (purity) is taken to be

$$p = \frac{\sum_{i\in \mathrm{s}} w_i}{\sum_{i\in \mathrm{s}} w_i + \sum_{i\in \mathrm{b}} w_i} \ , \tag{31}$$

where s and b refer to the signal and background event types. The weights are not strictly speaking necessary for a decision tree, but will be used in connection with boosting in Section 3.1.2. For a decision tree without boosting we can simply take all the weights to be equal.

To quantify the degree of separation achieved by a classifier for a selected subset of the events one can use, for example, the *Gini coefficient* [23], which historically has been used as a measure of dispersion in economics and is defined as

$$G = p(1-p) \ . \tag{32}$$

The Gini coefficient is zero if the selected sample is either pure signal or background. Another measure is simply the misclassification rate,

$$\varepsilon = 1 - \max(p, 1-p) \ . \tag{33}$$

The idea behind a decision tree is illustrated in Fig. 9, from an analysis by the MiniBooNE neutrino oscillation experiment at Fermilab [22].

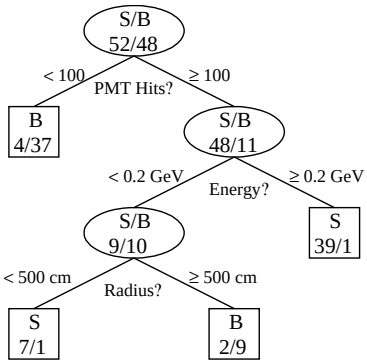

Fig. 9: Illustration of a decision tree used by the MiniBoone experiment [22] (see text).

One starts with the entire sample of training events in the root node, shown in the figure with 52 signal and 48 background events. Out of all of the possible input variables in the vector $\mathbf{x}$, one finds the component that provides the best separation between signal and background by use of a single cut. This requires a definition of what constitutes "best separation", and there are a number of reasonable choices. For example, for a cut that splits a set of events a into two subsets b and c, one can define the degree of separation through the weighted change in the Gini coefficients,

$$\Delta = W_a G_a - W_b G_b - W_c G_c \ . \tag{34}$$

where

$$W_a = \sum_{i \in a} w_i \ , \tag{35}$$

and similarly for W_b and W_c. Alternatively one may use a quantity similar to (34) but with, e.g., the misclassification rate (33) instead of the Gini coefficient. More possibilities can be found in Ref. [20].

For whatever chosen measure of degree of separation, Δ, one finds the cut on the variable amongst the components of $\mathbf{x}$ that maximizes it. In the example of the MiniBooNE experiment shown in Fig. 9, this happened to be a cut on the number of PMT hits with a value of 100. This splits the training sample into the two daughter nodes shown in the figure, one of which is enhanced in signal and the other in background events.

The algorithm requires a stopping rule based, e.g., on the number of events in a node or the misclassification rate. If, for example, the number of events or the misclassification rate in a given node falls below a certain threshold, then this defined as a terminal node or "leaf". It is classified as a signal or background leaf based on its predominant event type. In Fig. 9, for example, the node after the cut on PMT hits with 4 signal and 37 background events is classified as a terminal background node.

For nodes that have not yet reached the stopping criterion, one iterates the procedure and finds, as before, the variable that provides the best separation with a single cut. In Fig. 9 this is an energy cut of $0.2\,\mathrm{GeV}$. The steps are continued until all nodes reach the stopping criterion.

The resulting set of cuts effectively divides the $\mathbf{x}$ space into two regions: signal and background. To provide a numerical output for the classifier we can define

$$f(\mathbf{x}) = \begin{cases} 1 & \mathbf{x} \text{ in signal region,} \\ -1 & \mathbf{x} \text{ in background region.} \end{cases} \tag{36}$$

Equation (36) defines a decision tree classifier. In this form, these tend to be very sensitive to statistical fluctuations in the training data. One can easily see why this is, for example, if two of the components of $\mathbf{x}$ have similar discriminating power between signal and background. For a given training sample, one variable may be found to give the best degree of separation and is chosen to make the cut, and this affects the entire further structure of the tree. In a different statistically independent sample of training events, the other variable may be found to be better, and the resulting tree could look very different. Boosting is a technique that can decrease the sensitivity of a classifier to such fluctuations, and we describe this in the following section.

3.1.2 Boosting

Boosting is a general method of creating a set of classifiers which can be combined to give a new classifier that is more stable and has a smaller misclassification rate than any individual one. It is often applied to decision trees, precisely because they suffer from sensitivity to statistical fluctuations in the training sample, but the technique can be applied to any classifier.

Let us suppose as above that we have a sample of N training events, i.e., N instances of the data vector, $\mathbf{x}_1, \ldots, \mathbf{x}_N$, and N true class labels $y_1, \ldots, y_N$, with $y = 1$ for signal and $y = -1$ for background. Also as above assume we have N weights $w_1^{(1)}, \ldots, w_N^{(1)}$, where the superscript (1) refers to the fact that this is the first training set. We initially set the weights equal and normalized such that

$$\sum_{i=1}^{N} w_i^{(1)} = 1 \; . \tag{37}$$

The idea behind boosting is to create from the initial sample, a series of further training samples which differ from the initial one in that the weights will be changed according to a specific rule. A number of boosting algorithms have been developed, and these differ primarily in the rule used to update the weights. We will describe the AdaBoost algorithm of Freund and Schapire [24], as it was one of the first such algorithms and its properties have been well studied.

One begins with the initial training sample and from it derives a classifier. We have in mind here a decision tree, but it could be any type of classifier for where the training employs the event weights. The resulting function, $f_1(\mathbf{x})$ will have a certain misclassification rate ε_1. In general for the kth classifier (i.e., based on the kth training sample), we can write the error rate as

$$\varepsilon_k = \sum_{i=1}^{N} w_i^{(k)} I(y_i f_k(\mathbf{x}_i) \leq 0) \; , \tag{38}$$

where $I(X) = 1$ if the Boolean expression X is true, and is zero otherwise. We then assign a score to the classifier based on its error rate. For the AdaBoost algorithm this is

$$\alpha_k = \ln \frac{1 - \varepsilon_k}{\varepsilon_k} \; , \tag{39}$$

which is positive as long as the error rate is lower than 50%, i.e,. the classifier does better than random guessing.

Having carried out these steps for the initial training sample, we define the second training sample by updating the weights. More generally, the weights for step $k+1$ are found from those for step k by

$$w_i^{(k+1)} = w_i^{(k)} \, \frac{e^{-\alpha_k f_k(\mathbf{x}_i) y_i / 2}}{Z_k} \; , \tag{40}$$

where the factor Z_k is chosen so that the sum of the updated weights is equal to unity. Note that if an event is incorrectly classified, then the true class label y_i and the value $f_k(\mathbf{x}_i)$ have opposite signs, and thus the new weights are greater than the old ones. Correctly classified events have their weights decreased. This means that the updated training set will pay more attention in the next iteration to those events that were not correctly classified, the idea being that it should try harder to get it right the next time around.

After K iterations of this procedure one has classifiers $f_1(\mathbf{x}), \ldots, f_K(\mathbf{x})$, each with a certain error rate and score based on Eqs. (38) and (39). In the case of decision trees, the set of new trees is called a *forest*. From these one defines an averaged classifier as

$$y(\mathbf{x}) = \sum_{k=1}^{K} \alpha_k f_k(\mathbf{x}) \; . \tag{41}$$

Equation (41) defines a boosted decision tree (or more generally, a boosted version of whatever classifier was used).

One of the important questions to be addressed is how many boosting iterations to use. One can show that for a sufficiently large number of iterations, a boosted decision tree will eventually classify all of the events in the training sample correctly. Similar behaviour is found with any classification method where one can control to an arbitrary degree the flexibility of the decision boundary. The user can arrange so that the boundary twists and turns so as to get all of the events on the right side.

In the case of a neural network, for example, one can increase the number of hidden layers, or the number of nodes in the hidden layers; for a support vector machine, one can adjust the width of the kernel function and the regularization parameter to increase the flexibility of the boundary. An example is shown in Fig. 10(a), where an extremely flexible classifier has managed to enclose all of the signal events and exclude all of the background.

Of course if we were now to take the decision boundary shown in Fig. 10(a) and apply it to a statistically independent data sample, there is no reason to believe that the contortions that led to such good performance on the training sample will still work. This can be seen in Fig. 10(b), which shows the same boundary with a new data sample. In this case the classifier is said to be *overtrained*. Its error rate calculated from the same set of events used to train the classifier underestimates the rate on a statistically independent sample.

To deal with overtraining, one estimates the misclassification rate not only with the training data sample but also with a statistically independent test sample. We can then plot these rates as a function of the parameters that regulate the flexibility of the decision boundary, e.g., the number of boosting iterations used to form the BDT. For a small number of iterations, one will find in general that the error rates for both samples drop. The error rate based on the training sample will continue to drop, eventually reaching zero. But at some point the error rate from the test sample will cease to decrease and in general will increase. One chooses the architecture of the classifier (number of boosting iterations, number of nodes or layers in a neural network, etc.) to minimize the error rate on the test sample.

As the test sample is used to choose between a number of competing architectures based on the minimum observed error rate, this in fact gives biased estimate of the true error rate. In principle one

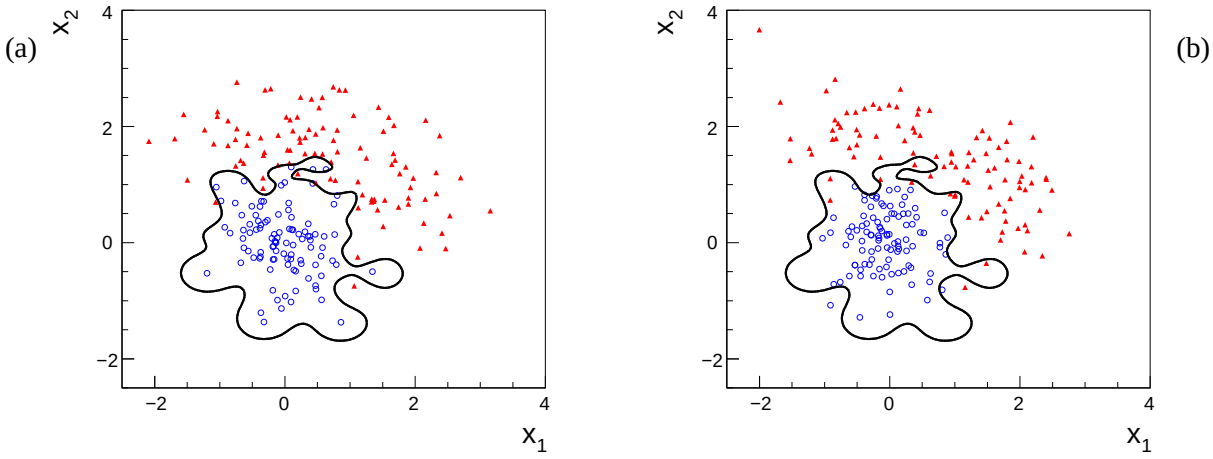

Fig. 10: Scatter plot of events of two types and the decision boundary determined by a particularly flexible classifier. Plot (a) shows the events used to train the classifier, and (b) shows an independent sample of test data.

should use a third validation sample to obtain an unbiased estimate of the error rate. In many cases the bias is small and this last step is omitted, but one should be aware of its potential existence.

In some applications, the training data is relatively inexpensive; one simply generates more events with Monte Carlo. But often event generation can take a prohibitively long time and one may be reluctant to use only a fraction of the events for training and the other half for testing. In such cases, procedures such as *cross validation* (see, e.g., [15, 16]) can be used where the available events are partitioned in a number of different ways into training and test samples and the results averaged.

Boosted decision trees have become increasingly popular in particle physics in recent years. One of their advantages is that they are relatively insensitive to the number of input variables used in the data vector $\mathbf{x}$. Components that provide little or no separation between signal and background are rarely chosen as for the cut that provides separation, i.e., to split the tree, and thus they are effectively ignored. Decision trees have no difficulty in dealing with different types of data; these can be real, integer, or they can simply be labels for which there is no natural ordering (categorical data). Furthermore, boosted decision trees are surprisingly insensitive to overtraining. That is, although the error rate on the test sample will not decrease to zero as one increases the number of boosting iterations (as is the case for the training sample), it tends not to increase. Further discussion of this point can be found in Ref. [25].

3.2 Summary on multivariate methods

The boosted decision tree is an example of a relatively modern development in Machine Learning that has attracted substantial attention in HEP. Support Vector Machines (SVMs) represent another such development and will no doubt also find further application in particle physics; further discussion on SVMs can be found in [15, 16] and references therein. Linear classifiers and neural networks will no doubt continue to play an important role, as will probability density estimation methods used to approximate the likelihood ratio.

Multivariate methods have the advantage of exploiting as much information as possible out of all of the quantities measured for each event. In an environment of competition between experiments, this can be a natural motivation to use them. Some caution should be exercised, however, before placing too much faith in the performance of a complicated classifier, to say nothing of a combination of complicated classifiers. These may have decision boundaries that indeed exploit nonlinear features of the training data, often based on Monte Carlo. But if these features have never been verified experimentally, then they may or may not be present in the real data. There is thus the risk of, say, underestimating the rate

of background events present in a region where one looks for signal, which could lead to a spurious discovery. Simpler classifiers are not immune to such dangers either, but in such cases the problems may be easier to control and mitigate.

One should therefore keep in mind the following quote, often heard in the multivariate analysis community:

> *Keep it simple. As simple as possible. Not any simpler.*
> — A. Einstein

To this we can add the more modern variant,

> *If you believe in something you don't understand, you suffer, . . .*
> —Stevie Wonder

Having made the requisite warnings, however, it seems clear that multivariate methods will play an important role in the discoveries we hope to make at the LHC. One can easily imagine, for example, that 5-sigma evidence for New Physics from a highly performant, and complicated, classifier would be regarded by the community with some scepticism. But if this is backed up by, say, 4-sigma significance from a simpler, more transparent analysis, then the conclusion would be more easily accepted, and the team that pursues both approaches may well win the race.

4 Summary and conclusions

In these lectures we have looked at two topics in statistics, Bayesian methods and multivariate analysis, which will play an important role in particle physics in the coming years. Bayesian methods provide important tools for analyzing systematic uncertainties, where prior information may be available that does not necessarily stem solely from other measurements, but rather from theoretical arguments or other indirect means. The Bayesian framework allows one to investigate how the posterior probabilities change upon variation of the prior probabilities. Through this type of sensitivity analysis, a Bayesian result becomes valuable to the broader scientific community.

As experiments become more expensive and the competition more intense, one will always be looking for ways to exploit as much information as possible from the data. Multivariate methods provide a means to achieve this, and advanced tools such as boosted decision trees have in recent years become widely used. And while their use will no doubt increase as the LHC experiments mature, one should keep in mind that a simple analysis also has its advantages. As one studies the advanced multivariate techniques, however, their properties become more apparent and the community will surely find ways of using them so as to maximize the benefits without excessive risk.

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